

Application/Control No.	Applicant(s)/Patent under Reexamination
09/901,289	PAN ET AL.
Examiner	Art Unit
Thien D. Tran	2665

	SEARCHED		
Class	Subclass	Date	Examiner
370	315	8/18/2005	тт
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
370	335	8/18/2005	тт
,	329, 320	8/18/2005	тт
	315	8/18/2005	TT

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST (USPGPUB, USPAT, EPO, DERWENT), 370/310, 320, 329, 335. See Search printout	8/18/2005	ΤТ		
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